

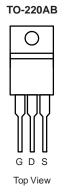
11N90L-TA3-T-VB Datasheet

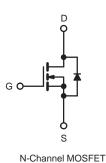
N-Channel 900V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	900				
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.95				
Q _g (Max.) (nC)	200				
Q _{gs} (nC)	24				
Q _{gd} (nC)	110				
Configuration	Sing	le			

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	900	- V	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 \degree C$	I _D	7.0		
	$T_{\rm C} = 100 ^{\circ}{\rm C}$		5.5	A	
Pulsed Drain Current ^a	I _{DM}	21	1		
Linear Derating Factor		1.5	W/°C		
Single Pulse Avalanche Energy ^b		E _{AS}	770	mJ	
Repetitive Avalanche Current ^a		I _{AR}	7.8	A	
Repetitive Avalanche Energy ^a		E _{AR}	19	mJ	
Maximum Power Dissipation $T_{C} = 25 \text{ °C}$		PD	190	W	
Peak Diode Recovery dV/dt ^c	dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) for 10 s			300 ^d		
Mounting Torque	6-32 or M3 screw		10	lbf · in	
Mounting Torque	0-32 OF IVIS SCREW		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/µs, V_{DD} \leq 600 V, T_J \leq 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

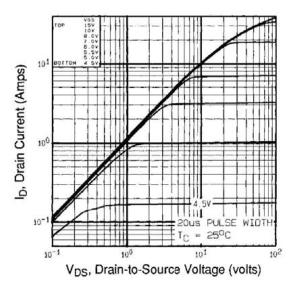


THERMAL RESISTANCE RATII		I							
PARAMETER	SYMBOL	TYP.		MAX.			UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		40					
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24		-			°C/W	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-		0.65					
SPECIFICATIONS (T _J = 25 °C, u	nless otherw	ise noted)							
PARAMETER	SYMBOL		TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								I	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 2	250 µA	900	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	l _D = 1 mA	-	0.98	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 2	250 µA	2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}		$V_{GS} = \pm 20$	V	-	-	± 100	nA	
		V _{DS} =	= 900 V, V _G	_S = 0 V	-	-	100		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V, T _J = 125 °C		-	-	500	μA		
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D		-	0.95	-	Ω	
Forward Transconductance	g fs	V _{DS} =	= 100 V, I _D =	= 5.6 A ^b	5.6	-	-	S	
Dynamic						I			
Input Capacitance	C _{iss}		$V_{aa} = 0.V$		-	3100	-		
Output Capacitance	C _{oss}		$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	800	-	pF	
Reverse Transfer Capacitance	C _{rss}	f = 1			-	490	-		
Total Gate Charge	Qg				-	-	200		
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13^{b}		-	-	24	nC	
Gate-Drain Charge	Q _{gd}		366 11	g. 0 and 15	-	-	110	1	
Turn-On Delay Time	t _{d(on)}				-	19	-		
Rise Time	tr		V _{DD} = 400 V, I _D = 5.6 A,		-	38	-	1	
Turn-Off Delay Time	t _{d(off)}	$V_{DD} = 400 \text{ V, } I_D = 5.6 \text{ A,} - R_g = 6.2 \Omega, R_D = 52 \Omega - See fig. 10^{\text{b}}$		120	-	ns			
Fall Time	t _f		see lig. To	-	-	39	-	1	
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") 1	from		-	5.0	-		
Internal Source Inductance	L _S	package and die contact	package and center of		-	13	-	nH	
Drain-Source Body Diode Characteristic	S								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	5.0				
Pulsed Diode Forward Currenta	I _{SM}			-	-	21	A		
Body Diode Voltage	V _{SD}	$T_{J} = 25 \ ^{\circ}C, I_{S} = 5.6 \ A, V_{GS} = 0 \ V^{b}$		-	-	1.8	V		
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 5.6 A, dl/dt = 100 A/μs ^b		-	650	980	ns		
Body Diode Reverse Recovery Charge	Q _{rr}				-	3.8	5.7	μC	
Forward Turn-On Time	t _{on}	Intrinsia tu	rn on timo i	s negligible (turn	on is do			<u> </u>	

Notes

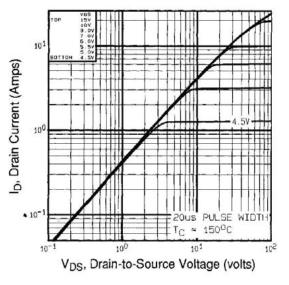
a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.





TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)







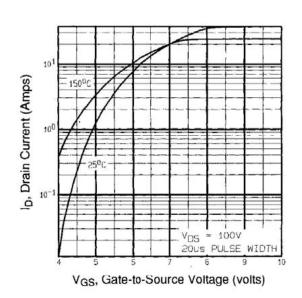
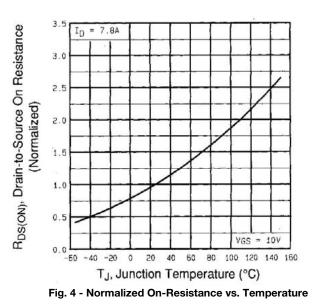


Fig. 3 - Typical Transfer Characteristics





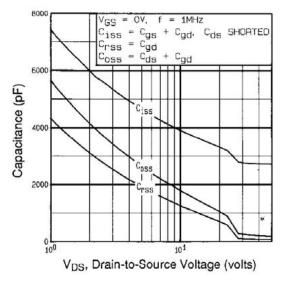
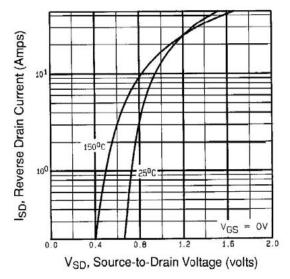


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





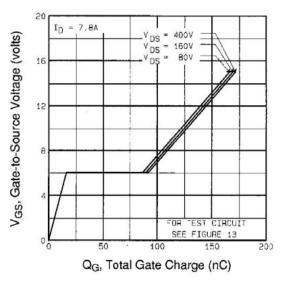
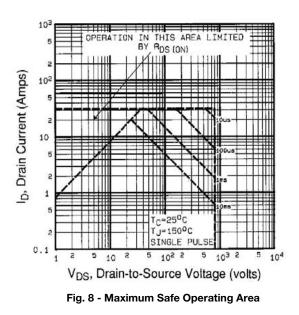


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





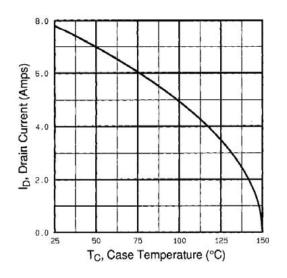


Fig. 9 - Maximum Drain Current vs. Case Temperature

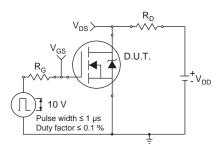


Fig. 10a - Switching Time Test Circuit

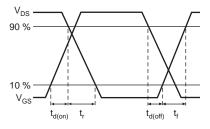


Fig. 10b - Switching Time Waveforms

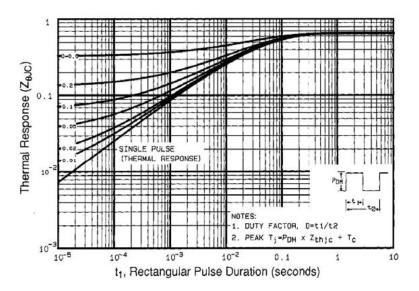


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



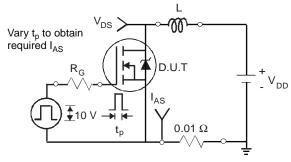


Fig. 12a - Unclamped Inductive Test Circuit

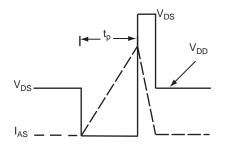


Fig. 12b - Unclamped Inductive Waveforms

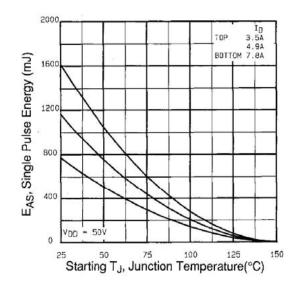


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

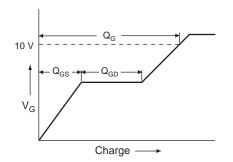


Fig. 13a - Basic Gate Charge Waveform

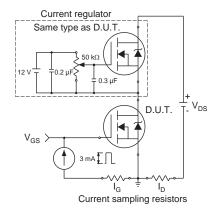
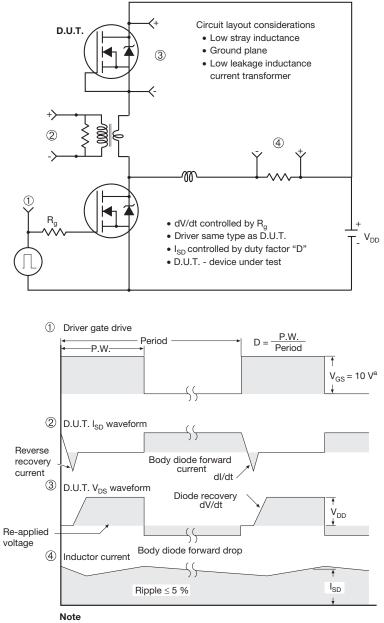


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit

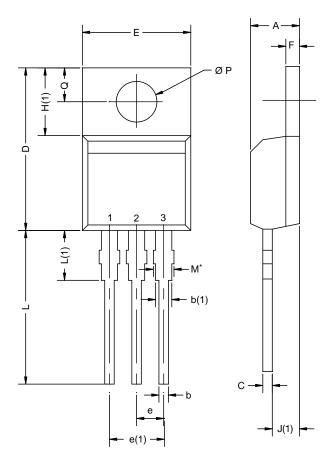


a. $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel



TO-220AB



	MILLIMETERS		INC	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
E	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØΡ	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12- DWG: 547	0208-Rev. N, 1	08-Oct-12				

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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